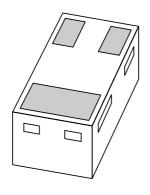
DISCRETE SEMICONDUCTORS

DATA SHEET



PBSS3540M 40 V, 0.5 A PNP low V_{CEsat} (BISS) transistor

Product data sheet 2003 Aug 12



40 V, 0.5 A PNP low V_{CEsat} (BISS) transistor

PBSS3540M

FEATURES

- Low collector-emitter saturation voltage V_{CEsat}
- High collector current capability I_C and I_{CM}
- High efficiency leading to reduced heat generation
- Reduced printed-circuit board requirements.

APPLICATIONS

- Power management:
 - DC-DC converter
 - Supply line switching
 - Battery charger
 - LCD backlighting.
- · Peripheral driver:
 - Driver in low supply voltage applications (e.g. lamps and LEDs).
 - Inductive load drivers (e.g. relays, buzzers and motors).

DESCRIPTION

Low V_{CEsat} PNP transistor in a SOT883 leadless ultra small plastic package.

NPN complement: PBSS2540M.

MARKING

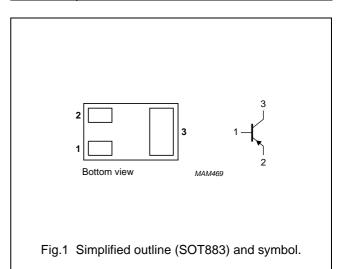
TYPE NUMBER	MARKING CODE
PBSS3540M	DA

QUICK REFERENCE DATA

SYMBOL	PARAMETER	MAX.	UNIT
V _{CEO}	collector-emitter voltage -40 V		
I _C	collector current (DC)	-500	mA
I _{CM}	peak collector current -1		Α
R _{CEsat}	equivalent on-resistance <700 m		mΩ

PINNING

PIN	DESCRIPTION	
1	base	
2	emitter	
3	collector	



2003 Aug 12

2

40 V, 0.5 A PNP low V_{CEsat} (BISS) transistor

PBSS3540M

LIMITING VALUES

In accordance with the Absolute Maximum Rating System (IEC 60134).

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.	UNIT
V _{CBO}	collector-base voltage	open emitter	_	-40	V
V _{CEO}	collector-emitter voltage	open base	_	-40	V
V _{EBO}	emitter-base voltage	open collector	_	-6	V
I _C	collector current (DC)	notes 1 and 2	_	-500	mA
I _{CM}	peak collector current		-	-1	Α
I _{BM}	peak base current		_	-100	mA
P _{tot}	total power dissipation	T _{amb} ≤ 25 °C; notes 1 and 2	_	250	mW
		T _{amb} ≤ 25 °C; note 1 and 3	-	430	mW
T _{stg}	storage temperature		-65	+150	°C
T _j	junction temperature		_	150	°C
T _{amb}	operating ambient temperature		-65	+150	°C

Notes

- 1. Refer to SOT883 standard mounting conditions.
- 2. Device mounted on an FR4 printed-circuit board, single-sided copper, tinplated, standard footprint, with 60 μ m copper strip line.
- 3. Device mounted on a printed-circuit board, single-sided copper, tinplated, mounting pad for collector 1 cm².

THERMAL CHARACTERISTICS

SYMBOL	PARAMETER	CONDITIONS	VALUE	UNIT
R _{th j-a}	thermal resistance from junction to	in free air; notes 1 and 2	500	K/W
	ambient	in free air; notes 1, 3 and 4	290	K/W

Notes

- 1. Refer to SOT883 standard mounting conditions.
- 2. Device mounted on an FR4 printed-circuit board, single-sided copper, tinplated, standard footprint, with 60 μm copper strip line.
- 3. Device mounted on a printed-circuit board, single-sided copper, tinplated, mounting pad for collector 1 cm².
- 4. Operated under pulsed conditions: duty cycle $\delta \leq$ 20%, pulse width $t_p \leq$ 30 ms.

Soldering

Reflow soldering is the only recommended soldering method.

40 V, 0.5 A PNP low V_{CEsat} (BISS) transistor

PBSS3540M

CHARACTERISTICS

 T_{amb} = 25 °C unless otherwise specified.

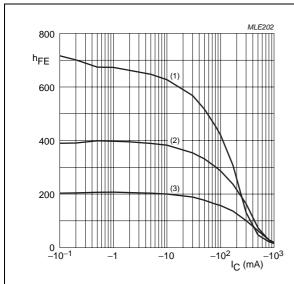
SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
I _{CBO}	collector-base cut-off current	$V_{CB} = -30 \text{ V}; I_E = 0$	_	_	-100	nA
		$V_{CB} = -30 \text{ V}; I_E = 0; T_j = 150 ^{\circ}\text{C}$	_	_	-50	μΑ
I _{EBO}	emitter-base cut-off current	$V_{EB} = -5 \text{ V}; I_C = 0$	_	_	-100	nA
h _{FE}	DC current gain	$V_{CE} = -2 \text{ V}; I_{C} = -10 \text{ mA}$	200	_	_	
		$V_{CE} = -2 \text{ V}; I_{C} = -100 \text{ mA}; \text{ note 1}$	150	_	_	
		$V_{CE} = -2 \text{ V}; I_{C} = -500 \text{ mA}; \text{ note 1}$	40	_	_	
V _{CEsat}	collector-emitter saturation voltage	$I_C = -10 \text{ mA}; I_B = -0.5 \text{ mA}$	_	_	-50	mV
		$I_C = -100 \text{ mA}; I_B = -5 \text{ mA}$	_	_	-130	mV
		$I_C = -200 \text{ mA}; I_B = -10 \text{ mA}$	_	_	-200	mV
		$I_C = -500 \text{ mA}$; $I_B = -50 \text{ mA}$; note 1	_	_	-350	mV
R _{CEsat}	equivalent on-resistance	$I_C = -500 \text{ mA}$; $I_B = -50 \text{ mA}$; note 1	_	440	<700	mΩ
V_{BEsat}	base-emitter saturation voltage	$I_C = -500 \text{ mA}$; $I_B = -50 \text{ mA}$; note 1	_	_	-1.2	V
V _{BEon}	base-emitter turn-on voltage	$V_{CE} = -2 \text{ V}; I_{C} = -100 \text{ mA}; \text{ note 1}$	_	_	-1.1	V
f⊤	transition frequency	$I_C = -100 \text{ mA}; V_{CE} = -5 \text{ V};$ f = 100 MHz	100	300	_	MHz
C _c	collector capacitance	$V_{CB} = -10 \text{ V}; I_E = I_e = 0; f = 1 \text{ MHz}$	_	_	10	pF

Note

1. Pulse test: $t_p \le 300~\mu s;~\delta \le 0.02.$

40 V, 0.5 A PNP low V_{CEsat} (BISS) transistor

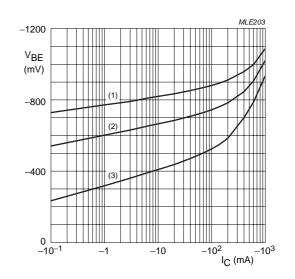
PBSS3540M



 $V_{CE} = -2 V$.

- (1) $T_{amb} = 150 \, ^{\circ}C$.
- (2) $T_{amb} = 25 \, ^{\circ}C$.
- (3) $T_{amb} = -55 \, ^{\circ}C$.

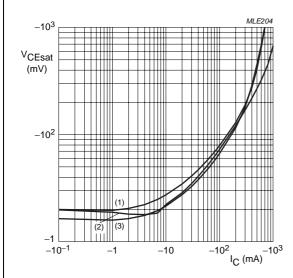
Fig.2 DC current gain as a function of collector current; typical values.



 $V_{CE} = -2 \text{ V}.$

- (1) $T_{amb} = -55 \, ^{\circ}C$.
- (2) T_{amb} = 25 °C.
- (3) $T_{amb} = 150 \, ^{\circ}C$.

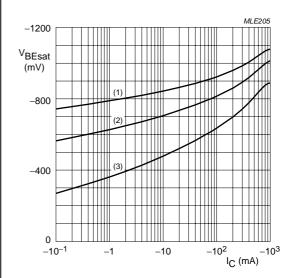
Fig.3 Base-emitter voltage as a function of collector current; typical values.



 $I_{\rm C}/I_{\rm B} = 20.$

- (1) $T_{amb} = 150 \, ^{\circ}C$.
- (2) $T_{amb} = 25 \, ^{\circ}C$.
- (3) $T_{amb} = -55 \, ^{\circ}C$.

Fig.4 Collector-emitter saturation voltage as a function of collector current; typical values.



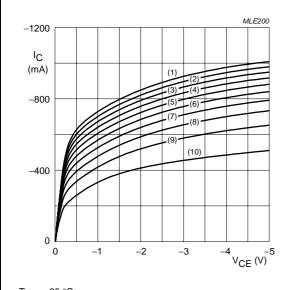
 $I_{\rm C}/I_{\rm B} = 20$.

- (1) T_{amb} = 150 °C.
- (2) $T_{amb} = 25 \, ^{\circ}C$.
- (3) $T_{amb} = -55 \, ^{\circ}C$.

Fig.5 Base-emitter saturation voltage as a function of collector current; typical values.

40 V, 0.5 A PNP low V_{CEsat} (BISS) transistor

PBSS3540M



 $T_{amb} = 25 \, ^{\circ}C.$

(1) $I_B = -40 \text{ mA}.$

(5) $I_B = -24 \text{ mA}.$

(9) $I_B = -8 \text{ mA}.$ (10) $I_B = -4 \text{ mA}.$

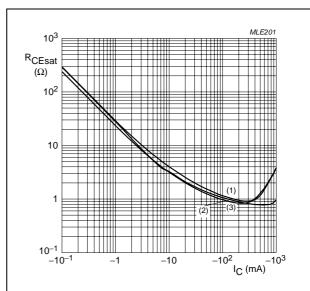
(2) $I_B = -36 \text{ mA}.$

(6) $I_B = -20 \text{ mA}.$ (7) $I_B = -16 \text{ mA}.$

(3) $I_B = -32 \text{ mA}.$ (4) $I_B = -28 \text{ mA}.$

(8) $I_B = -12 \text{ mA}.$

Fig.6 Collector current as a function of collector-emitter voltage; typical values.



 $I_{\rm C}/I_{\rm B}=20.$

(1) $T_{amb} = 150 \, ^{\circ}C$.

(2) $T_{amb} = 25 \, ^{\circ}C$.

(3) $T_{amb} = -55 \, ^{\circ}C$.

Fig.7 Collector-emitter equivalent on-resistance as a function of collector current; typical values.

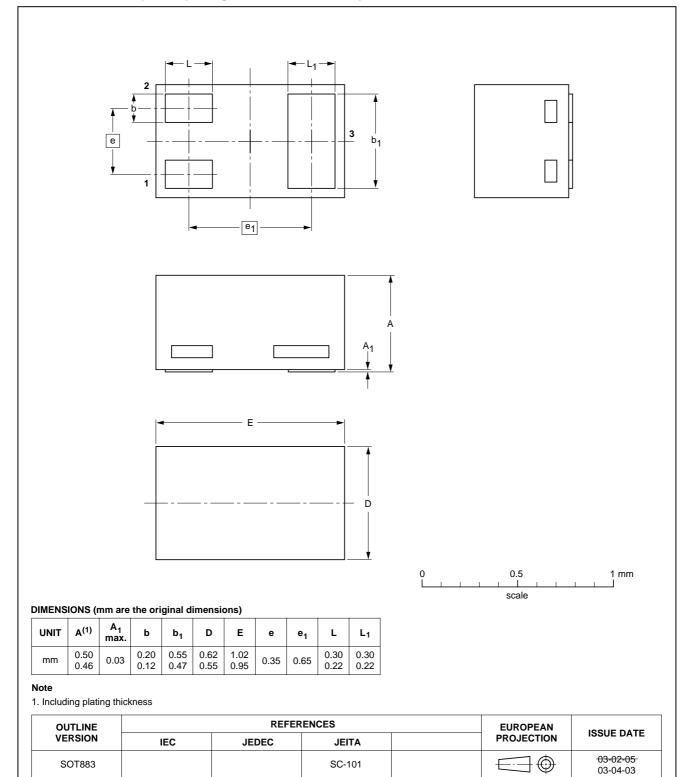
40 V, 0.5 A PNP low V_{CEsat} (BISS) transistor

PBSS3540M

PACKAGE OUTLINE

Leadless ultra small plastic package; 3 solder lands; body 1.0 x 0.6 x 0.5 mm

SOT883



40 V, 0.5 A PNP low V_{CEsat} (BISS) transistor

PBSS3540M

DATA SHEET STATUS

DOCUMENT STATUS ⁽¹⁾	PRODUCT STATUS ⁽²⁾	DEFINITION
Objective data sheet	Development	This document contains data from the objective specification for product development.
Preliminary data sheet	Qualification	This document contains data from the preliminary specification.
Product data sheet	Production	This document contains the product specification.

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